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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	e200z4d
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, LINbus, SCI, SPI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	57
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.63V
Data Converters	A/D 32x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc564l60l3bcoqr

1.3 Device comparison

Table 1. SPC56ELx/SPC564Lx device summary

Feature		SPC56EL60	SPC56EL54
CPU	Type	2 × e200z4 (in lock-step or decoupled operation)	
	Architecture	Harvard	
	Execution speed	0–120 MHz (+2% FM)	
	DMIPS intrinsic performance	>240 MIPS	
	SIMD (DSP + FPU)	Yes	
	MMU	16 entry	
	Instruction set PPC	Yes	
	Instruction set VLE	Yes	
	Instruction cache	4 KB, EDC	
	MPU-16 regions	Yes, replicated module	
	Semaphore unit (SEMA4)	Yes	
Buses	Core bus	AHB, 32-bit address, 64-bit data	
	Internal periphery bus	32-bit address, 32-bit data	
Crossbar	Master × slave ports	Lock Step Mode: 4 × 3 Decoupled Parallel Mode: 6 × 3	
Memory	Flash	1 MB, ECC, RWW	768 KB, ECC, RWW
	Static RAM (SRAM)	128 KB, ECC	96 KB, ECC

exceptions, etc.), allowing the development tool to interpolate what transpires between the discontinuities. Thus, static code may be traced.
  - Watchpoint messaging (WPM) via the auxiliary port
  - Watchpoint trigger enable of program and/or data trace messaging
  - Data tracing of instruction fetches via private opcodes

1.5.39 IEEE 1149.1 JTAG Controller (JTAGC)

The JTAGC block provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode. All data input to and output from the JTAGC block is communicated in serial format. The JTAGC block is compliant with the IEEE standard.

The JTAG controller provides the following features:

- IEEE Test Access Port (TAP) interface with 5 pins:
  - TDI
  - TMS
  - TCK
  - TDO
  - JCOMP
- Selectable modes of operation include JTAGC/debug or normal system operation
- 5-bit instruction register that supports the following IEEE 1149.1-2001 defined instructions:
  - BYPASS
  - IDCODE
  - EXTEST
  - SAMPLE
  - SAMPLE/PRELOAD
- 3 test data registers: a bypass register, a boundary scan register, and a device identification register. The size of the boundary scan register is parameterized to support a variety of boundary scan chain lengths.
- TAP controller state machine that controls the operation of the data registers, instruction register and associated circuitry

Table 4. LQFP144 pin function summary (continued)

Pin #	Port/function	Peripheral	Output function	Input function
34	D[6]	SIUL	GPIO[54]	GPIO[54]
		DSPI_0	CS2	—
		FlexPWM_0	X[3]	X[3]
		FlexPWM_0	—	FAULT[1]
35	$V_{SS\_LV\_PLL0\_PLL1}$	—		
36	$V_{DD\_LV\_PLL0\_PLL1}$	—		
37	D[7]	SIUL	GPIO[55]	GPIO[55]
		DSPI_1	CS3	—
		DSPI_0	CS4	—
		SWG	analog output	—
38	FCCU_F[0]	FCCU	F[0]	F[0]
39	$V_{DD\_LV\_COR}$	—		
40	$V_{SS\_LV\_COR}$	—		
41	C[1]	SIUL	—	GPIO[33]
		ADC_0	—	AN[2]
42	E[4]	SIUL	—	GPIO[68]
		ADC_0	—	AN[7]
43	B[7]	SIUL	—	GPIO[23]
		LINFlexD_0	—	RXD
		ADC_0	—	AN[0]
44	E[5]	SIUL	—	GPIO[69]
		ADC_0	—	AN[8]
45	C[2]	SIUL	—	GPIO[34]
		ADC_0	—	AN[3]
46	E[6]	SIUL	—	GPIO[70]
		ADC_0	—	AN[4]
47	B[8]	SIUL	—	GPIO[24]
		eTimer_0	—	ETC[5]
		ADC_0	—	AN[1]
48	E[7]	SIUL	—	GPIO[71]
		ADC_0	—	AN[6]
49	E[2]	SIUL	—	GPIO[66]
		ADC_0	—	AN[5]
50	$V_{DD\_HV\_ADR0}$	—		
51	$V_{SS\_HV\_ADR0}$	—		

Table 4. LQFP144 pin function summary (continued)

Pin #	Port/function	Peripheral	Output function	Input function
52	B[9]	SIUL	—	GPIO[25]
		ADC_0 ADC_1	—	AN[11]
53	B[10]	SIUL	—	GPIO[26]
		ADC_0 ADC_1	—	AN[12]
54	B[11]	SIUL	—	GPIO[27]
		ADC_0 ADC_1	—	AN[13]
55	B[12]	SIUL	—	GPIO[28]
		ADC_0 ADC_1	—	AN[14]
56	$V_{DD\_HV\_ADR1}$	—		
57	$V_{SS\_HV\_ADR1}$	—		
58	$V_{DD\_HV\_ADV}$	—		
59	$V_{SS\_HV\_ADV}$	—		
60	B[13]	SIUL	—	GPIO[29]
		LINFlexD_1	—	RXD
		ADC_1	—	AN[0]
61	E[9]	SIUL	—	GPIO[73]
		ADC_1	—	AN[7]
62	B[15]	SIUL	—	GPIO[31]
		SIUL	—	EIRQ[20]
		ADC_1	—	AN[2]
63	E[10]	SIUL	—	GPIO[74]
		ADC_1	—	AN[8]
64	B[14]	SIUL	—	GPIO[30]
		eTimer_0	—	ETC[4]
		SIUL	—	EIRQ[19]
		ADC_1	—	AN[1]
65	E[11]	SIUL	—	GPIO[75]
		ADC_1	—	AN[4]
66	C[0]	SIUL	—	GPIO[32]
		ADC_1	—	AN[3]
67	E[12]	SIUL	—	GPIO[76]
		ADC_1	—	AN[6]

Table 5. LFBGA257 pin function summary (continued)

Pin #	Port/function	Peripheral	Output function	Input function
C9	I[0]	SIUL	GPIO[128]	GPIO[128]
		eTimer_2	ETC[0]	ETC[0]
		DSPI_0	CS4	—
		FlexPWM_1	—	FAULT[0]
C10	JCOMP	—	—	JCOMP
C11	H[11]	SIUL	GPIO[123]	GPIO[123]
		FlexPWM_1	A[2]	A[2]
C12	I[1]	SIUL	GPIO[129]	GPIO[129]
		eTimer_2	ETC[1]	ETC[1]
		DSPI_0	CS5	—
		FlexPWM_1	—	FAULT[1]
C13	F[14]	SIUL	GPIO[94]	GPIO[94]
		LINFlexD_1	TXD	—
C14	B[1]	SIUL	GPIO[17]	GPIO[17]
		eTimer_1	ETC[3]	ETC[3]
		SSCM	DEBUG[1]	—
		FlexCAN_0	—	RXD
		FlexCAN_1	—	RXD
		SIUL	—	EIRQ[16]
C15	$V_{SS\_HV\_IO\_RING}$	—		
C16	A[4]	SIUL	GPIO[4]	GPIO[4]
		eTimer_1	ETC[0]	ETC[0]
		DSPI_2	CS1	—
		eTimer_0	ETC[4]	ETC[4]
		MC_RGM	—	FAB
		SIUL	—	EIRQ[4]
C17	F[12]	SIUL	GPIO[92]	GPIO[92]
		eTimer_1	ETC[3]	ETC[3]
		SIUL	—	EIRQ[30]
D1	F[5]	SIUL	GPIO[85]	GPIO[85]
		NPC	MDO[2]	—
D2	F[4]	SIUL	GPIO[84]	GPIO[84]
		NPC	MDO[3]	—

Table 5. LFBGA257 pin function summary (continued)

Pin #	Port/function	Peripheral	Output function	Input function
N14	Not connected	—		
N15	C[12]	SIUL	GPIO[44]	GPIO[44]
		eTimer_0	ETC[5]	ETC[5]
		DSPI_2	CS3	—
N16	A[2]	SIUL	GPIO[2]	GPIO[2]
		eTimer_0	ETC[2]	ETC[2]
		FlexPWM_0	A[3]	A[3]
		DSPI_2	—	SIN
		MC_RGM	—	ABS[0]
		SIUL	—	EIRQ[2]
N17	G[5]	SIUL	GPIO[101]	GPIO[101]
		FlexPWM_0	X[3]	X[3]
		DSPI_2	CS3	—
P1	$V_{SS\_HV\_OSC}$	—		
P2	RESET	—		
P3	D[6]	SIUL	GPIO[54]	GPIO[54]
		DSPI_0	CS2	—
		FlexPWM_0	X[3]	X[3]
		FlexPWM_0	—	FAULT[1]
P4	$V_{DD\_LV\_PLL0\_PLL1}$	—		
P5	$V_{DD\_LV\_CORE\_RING}$	—		
P6	$V_{SS\_LV\_CORE\_RING}$	—		
P7	B[8]	SIUL	—	GPIO[24]
		eTimer_0	—	ETC[5]
		ADC_0	—	AN[1]
P8	Not connected	—		
P9	$V_{SS\_HV\_IO\_RING}$	—		
P10	$V_{DD\_HV\_IO\_RING}$	—		
P11	B[14]	SIUL	—	GPIO[30]
		eTimer_0	—	ETC[4]
		SIUL	—	EIRQ[19]
		ADC_1	—	AN[1]
P12	$V_{DD\_LV\_CORE\_RING}$	—		
P13	$V_{SS\_LV\_CORE\_RING}$	—		
P14	$V_{DD\_HV\_IO\_RING}$	—		

2. This pad contains a weak pull-up.
3. EXTAL is an "Output" in "crystal" mode, and is an "Input" in "ext clock" mode.
4. In XOSC Bypass Mode, the analog portion of crystal oscillator (amplifier) is disabled. An external clock can be applied at EXTAL as an input. In XOSC Normal Mode, EXTAL is an output
5. This pad contains a weak pull-down.
6. RESET output shall be considered valid only after the 3.3V supply reaches its stable value.

Note: None of system pins (except RESET) provides an open drain output.

2.4 Pin muxing

Table 8 defines the pin list and muxing for this device.

Each entry of *Table 8* shows all the possible configurations for each pin, via the alternate functions. The default function assigned to each pin after reset is indicated by ALT0.

Note: Pins labeled “NC” are to be left unconnected. Any connection to an external circuit or voltage may cause unpredictable device behavior or damage.

Note: Pins labeled “Reserved” are to be tied to ground. Not doing so may cause unpredictable device behavior.

Table 8. Pin muxing (continued)

Port name	PCR	Peripheral	Alternate output function	Output mux sel	Input functions	Input mux select	Weak pull config during reset	Pad speed(1)		Pin #		
								SRC = 1	SRC = 0	100 pkg	144 pkg	257 pkg
C[10]	PCR[42]	SIUL	GPIO[42]	ALT0	GPIO[42]	—	—	M	S	78	111	A15
		DSPI_2	CS2	ALT1	—	—						
		FlexPWM_0	A[3]	ALT3	A[3]	PSMI[23]; PADSEL=1						
		FlexPWM_0	—	—	FAULT[1]	PSMI[17]; PADSEL=0						
C[11]	PCR[43]	SIUL	GPIO[43]	ALT0	GPIO[43]	—	—	M	S	55	80	M14
		eTimer_0	ETC[4]	ALT1	ETC[4]	PSMI[7]; PADSEL=1						
		DSPI_2	CS2	ALT2	—	—						
C[12]	PCR[44]	SIUL	GPIO[44]	ALT0	GPIO[44]	—	—	M	S	56	82	N15
		eTimer_0	ETC[5]	ALT1	ETC[5]	PSMI[8]; PADSEL=0						
		DSPI_2	CS3	ALT2	—	—						
C[13]	PCR[45]	SIUL	GPIO[45]	ALT0	GPIO[45]	—	—	M	S	71	101	F15
		eTimer_1	ETC[1]	ALT1	ETC[1]	PSMI[10]; PADSEL=0						
		CTU_0	—	—	EXT_IN	PSMI[0]; PADSEL=0						
		FlexPWM_0	—	—	EXT_SYNC	PSMI[15]; PADSEL=0						
C[14]	PCR[46]	SIUL	GPIO[46]	ALT0	GPIO[46]	—	—	M	S	72	103	E15
		eTimer_1	ETC[2]	ALT1	ETC[2]	PSMI[11]; PADSEL=1						
		CTU_0	EXT_TGR	ALT2	—	—						

Table 8. Pin muxing (continued)

Port name	PCR	Peripheral	Alternate output function	Output mux sel	Input functions	Input mux select	Weak pull config during reset	Pad speed(1)		Pin #		
								SRC = 1	SRC = 0	100 pkg	144 pkg	257 pkg
D[2]	PCR[50]	SIUL	GPIO[50]	ALT0	GPIO[50]	—	—	M	S	—	140	C5
		eTimer_1	ETC[3]	ALT2	ETC[3]	PSMI[12]; PADSEL=1						
		FlexPWM_0	X[3]	ALT3	X[3]	PSMI[30]; PADSEL=0						
		FlexRay	—	—	CB_RX	—						
D[3]	PCR[51]	SIUL	GPIO[51]	ALT0	GPIO[51]	—	—	SYM	S	89	128	A7
		FlexRay	CB_TX	ALT1	—	—						
		eTimer_1	ETC[4]	ALT2	ETC[4]	PSMI[13]; PADSEL=1						
		FlexPWM_0	A[3]	ALT3	A[3]	PSMI[23]; PADSEL=2						
D[4]	PCR[52]	SIUL	GPIO[52]	ALT0	GPIO[52]	—	—	SYM	S	90	129	B7
		FlexRay	CB_TR_EN	ALT1	—	—						
		eTimer_1	ETC[5]	ALT2	ETC[5]	PSMI[14]; PADSEL=2						
		FlexPWM_0	B[3]	ALT3	B[3]	PSMI[27]; PADSEL=2						
D[5]	PCR[53]	SIUL	GPIO[53]	ALT0	GPIO[53]	—	—	M	S	22	33	N3
		DSPI_0	CS3	ALT1	—	—						
		FlexPWM_0	—	—	FAULT[2]	PSMI[18]; PADSEL=0						

Table 8. Pin muxing (continued)

Port name	PCR	Peripheral	Alternate output function	Output mux sel	Input functions	Input mux select	Weak pull config during reset	Pad speed(1)		Pin #		
								SRC = 1	SRC = 0	100 pkg	144 pkg	257 pkg
D[6]	PCR[54]	SIUL	GPIO[54]	ALT0	GPIO[54]	—	—	M	S	23	34	P3
		DSPI_0	CS2	ALT1	—	—						
		FlexPWM_0	X[3]	ALT3	X[3]	PSMI[30]; PADSEL=1						
		FlexPWM_0	—	—	FAULT[1]	PSMI[17]; PADSEL=1						
D[7]	PCR[55]	SIUL	GPIO[55]	ALT0	GPIO[55]	—	—	M	S	26	37	R4
		DSPI_1	CS3	ALT1	—	—						
		DSPI_0	CS4	ALT3	—	—						
		SWG	analog output	—	—	—						
D[8]	PCR[56]	SIUL	GPIO[56]	ALT0	GPIO[56]	—	—	M	S	21	32	M3
		DSPI_1	CS2	ALT1	—	—						
		eTimer_1	ETC[4]	ALT2	ETC[4]	PSMI[13]; PADSEL=2						
		DSPI_0	CS5	ALT3	—	—						
		FlexPWM_0	—	—	FAULT[3]	PSMI[19]; PADSEL=1						
D[9]	PCR[57]	SIUL	GPIO[57]	ALT0	GPIO[57]	—	—	M	S	15	26	L3
		FlexPWM_0	X[0]	ALT1	X[0]	—						
		LINFlexD_1	TXD	ALT2	—	—						

Table 8. Pin muxing (continued)

Port name	PCR	Peripheral	Alternate output function	Output mux sel	Input functions	Input mux select	Weak pull config during reset	Pad speed(1)		Pin #		
								SRC = 1	SRC = 0	100 pkg	144 pkg	257 pkg
H[11]	PCR[123]	SIUL	GPIO[123]	ALT0	GPIO[123]	—	—	M	S	—	—	C11
		FlexPWM_1	A[2]	ALT1	A[2]	—						
H[12]	PCR[124]	SIUL	GPIO[124]	ALT0	GPIO[124]	—	—	M	S	—	—	B10
		FlexPWM_1	B[2]	ALT1	B[2]	—						
H[13]	PCR[125]	SIUL	GPIO[125]	ALT0	GPIO[125]	—	—	M	S	—	—	G15
		FlexPWM_1	X[3]	ALT1	X[3]	—						
		eTimer_2	ETC[3]	ALT2	ETC[3]	PSMI[42]; PADSEL=0						
H[14]	PCR[126]	SIUL	GPIO[126]	ALT0	GPIO[126]	—	—	M	S	—	—	A12
		FlexPWM_1	A[3]	ALT1	A[3]	—						
		eTimer_2	ETC[4]	ALT2	ETC[4]	—						
H[15]	PCR[127]	SIUL	GPIO[127]	ALT0	GPIO[127]	—	—	M	S	—	—	J17
		FlexPWM_1	B[3]	ALT1	B[3]	—						
		eTimer_2	ETC[5]	ALT2	ETC[5]	—						
Port I												
I[0]	PCR[128]	SIUL	GPIO[128]	ALT0	GPIO[128]	—	—	M	S	—	—	C9
		eTimer_2	ETC[0]	ALT1	ETC[0]	PSMI[39]; PADSEL=1						
		DSPI_0	CS4	ALT2	—	—						
		FlexPWM_1	—	—	FAULT[0]	—						

Table 9. Absolute maximum ratings(1) (continued)

Symbol		Parameter	Conditions	Min	Max	Unit
$V_{SS\_HV\_ADR0}$ $V_{SS\_HV\_ADR1}$	SR	ADC_0 ground and low reference voltage ADC_1 ground and low reference voltage	—	–0.1	0.1	V
$V_{DD\_HV\_ADV}$	SR	3.3 V ADC supply voltage	—	–0.3	4.5 (4), (3)	V
$V_{SS\_HV\_ADV}$	SR	3.3 V ADC supply ground	—	–0.1	0.1	V
TV_{DD}	SR	Supply ramp rate	—	3.0×10^{-6} (3.0 V/sec)	0.5 V/µs	V/µs
V_{IN}	SR	Voltage on any pin with respect to ground ($V_{SS\_HV\_IOx}$) or $V_{ss\_HV\_ADRx}$	Valid only for ADC pins	–0.3	6.0 (4)	V
			Relative to V_{DD}	–0.3	V_{DD} + 0.3(4), (5)	
I_{INJPAD}	SR	Injected input current on any pin during overload condition	—	–10	10	mA
I_{INJSUM}	SR	Absolute sum of all injected input currents during overload condition	—	–50	50	mA
T_{STG}	SR	Storage temperature	—	–55	150	°C

1. Functional operating conditions are given in the DC electrical characteristics. Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Exposure to absolute maximum rating conditions for extended periods may affect device reliability or cause permanent damage to the device.
2. Any voltage between operating condition and absolute max rating can be sustained for maximum cumulative time of 10 hours.
3. Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.
4. Internal structures hold the input voltage less than the maximum voltage on all pads powered by VDDE supplies, if the maximum injection current specification is met and VDDE is within the operating voltage specifications.
5. V_{DD} has to be considered equal to $V_{DD\_HV\_ADRx}$ in case of ADC pins, whilst it is $V_{DD\_HV\_IOx}$ for any other pin.

3.3 Recommended operating conditions

Table 10. Recommended operating conditions (3.3 V)

Symbol		Parameter	Conditions	Min(1)	Max	Unit
$V_{DD\_HV\_REG}$	SR	3.3 V voltage regulator supply voltage	—	3.0	3.63	V
$V_{DD\_HV\_IOx}$	SR	3.3 V input/output supply voltage	—	3.0	3.63	V
$V_{SS\_HV\_IOx}$	SR	Input/output ground voltage	—	0	0	V
$V_{DD\_HV\_FLA}$	SR	3.3 V flash supply voltage	—	3.0	3.63	V
$V_{SS\_HV\_FLA}$	SR	Flash memory ground	—	0	0	V
$V_{DD\_HV\_OSC}$	SR	3.3 V crystal oscillator amplifier supply voltage	—	3.0	3.63	V
$V_{SS\_HV\_OSC}$	SR	3.3 V crystal oscillator amplifier reference voltage	—	0	0	V
$V_{DD\_HV\_ADR0}$(2), (3) $V_{DD\_HV\_ADR1}$	SR	3.3 V / 5.0 V ADC_0 high reference voltage 3.3 V / 5.0 V ADC_1 high reference voltage	—	4.5 to 5.5 or 3.0 to 3.63		V

Table 10. Recommended operating conditions (3.3 V) (continued)

Symbol		Parameter	Conditions	Min(1)	Max	Unit
$V_{DD\_HV\_ADV}$	SR	3.3 V ADC supply voltage	—	3.0	3.63	V
$V_{SS\_HV\_AD0}$ $V_{SS\_HV\_AD1}$	SR	ADC_0 ground and low reference voltage ADC_1 ground and low reference voltage	—	0	0	V
$V_{SS\_HV\_ADV}$	SR	3.3 V ADC supply ground	—	0	0	V
$V_{DD\_LV\_REGCOR}$(4)	SR	Internal supply voltage	—	—	—	V
$V_{SS\_LV\_REGCOR}$(5)	SR	Internal reference voltage	—	0	0	V
$V_{DD\_LV\_CORx}$(2)	SR	Internal supply voltage	—	—	—	V
$V_{SS\_LV\_CORx}$(3)	SR	Internal reference voltage	—	0	0	V
$V_{DD\_LV\_PLL}$(2)	SR	Internal supply voltage	—	—	—	V
$V_{SS\_LV\_PLL}$(3)	SR	Internal reference voltage	—	0	0	V
T_A	SR	Ambient temperature under bias	$f_{CPU} \leq 120$ MHz	–40	125	°C
T_J	SR	Junction temperature under bias	—	–40	150	°C

1. Full functionality cannot be guaranteed when voltage drops below 3.0 V. In particular, ADC electrical characteristics and I/Os DC electrical specification may not be guaranteed.
2. $V_{DD\_HV\_ADR0}$ and $V_{DD\_HV\_ADR1}$ cannot be operated at different voltages, and need to be supplied by the same voltage source.
3. $V_{DD\_HV\_ADRx}$ must always be applied and should be stable before LBIST starts. If this supply is not above its absolute minimum level, LBIST operations can fail.
4. Can be connected to emitter of external NPN. Low voltage supplies are not under user control. They are produced by an on-chip voltage regulator.
5. For the device to function properly, the low voltage grounds ($V_{SS\_LV\_xxx}$) must be shorted to high voltage grounds ($V_{SS\_HV\_xxx}$) and the low voltage supply pins ($V_{DD\_LV\_xxx}$) must be connected to the external ballast emitter, if one is used.

3.4 Decoupling capacitors

The internal voltage regulator requires an external NPN ballast and some additional decoupling capacitors. These capacitors shall be placed on the board as close as possible to the associated pin.

Table 11. Decoupling capacitors

Symbol		Parameter	Conditions(1)	Value			Unit
				Min	Typ	Max	
C_{COL}	SR	External decoupling / stability capacitor	Accuracy -50%/+35%. Max ESR = 100 mΩ.		20		µF
C_{LV1}	SR	External decoupling / stability capacitor	Sum of C_{LV1} placed close to $V_{DD}/V_{SS\_LV\_CORy}$ pairs(2).	12µF		40µF	µF
C_{LV2}	SR	External decoupling / stability capacitor	Sum of C_{LV2} placed close to $V_{DD}/V_{SS\_LV\_CORy}$ pairs shall be between 300 nF and 900 nF.		100(2)		nF

SPC56XL60/54 makes a transition from HPREG1 to HPREG2. This transition is dynamic. Once HPREG2 is fully operational, the controller part of HPREG1 is switched off.

The following bipolar transistors are supported:

- BCP68 from ON Semiconductor
- BCX68 from Infineon

Table 19. Characteristics

Symbol	Parameter	Value	Unit
$h_{FE}(\beta)$	DC current gain (Beta)	85 - 375	—
P_D	Maximum power dissipation @ T_A=25°C(1)	1.5	W
I_{CMaxDC}	Maximum peak collector current	1.0	A
VCE_{SAT}	Collector-to-emitter saturation voltage (Max)	600(2)	mV
V_{BE}	Base-to-emitter voltage (Max)	1.0	V

1. Derating factor 12mW/degC.
2. Adjust resistor at bipolar transistor collector for 3.3V to avoid VCE<VCE_{SAT}.

The recommended external ballast transistor is the bipolar transistor BCP68 with the gain range of 85 up to 375 (for IC=500mA, VCE=1V) provided by several suppliers. This includes the gain variations BCP68-10, BCP68-16 and BCP68-25.The most important parameters for the interoperability with the integrated voltage regulator are the DC current gain (hFE) and the temperature coefficient of the gain (XTB). While the specified gain range of most BCP68 vendors is the same, there are slight variations in the temperature coefficient parameter. SPC56XL60/54 Voltage regulator operation was simulated against the typical variation on temperature coefficient and against the specified gain range to have a robust design.

Table 20. Voltage regulator electrical specifications

Symbol		Parameter	Conditions	Min	Typ	Max	Unit
C_{ext}		External decoupling/ stability capacitor	Min, max values shall be granted with respect to tolerance, voltage, temperature, and aging variations.	12	—	40	µF
	SR	Combined ESR of external capacitor	—	1	—	100	mΩ
	SR	Number of pins for external decoupling/ stability capacitor	—	5	—	—	—
C_{V1V2}	SR	Total capacitance on 1.2 V pins	Ceramic capacitors, taking into account tolerance, aging, voltage and temperature variation	300	—	900	nF
t_{SU}		Start-up time after main supply stabilization	C_{load} = 10 µF × 4	—	—	2.5	ms

twice the conversion period (T_C). Again the conversion period T_C is longer than the sampling time T_S, which is just a portion of it, even when fixed channel continuous conversion mode is selected (fastest conversion rate at a specific channel): in conclusion it is evident that the time constant of the filter $R_F C_F$ is definitively much higher than the sampling time T_S, so the charge level on C_S cannot be modified by the analog signal source during the time in which the sampling switch is closed.

The considerations above lead to impose new constraints on the external circuit, to reduce the accuracy error due to the voltage drop on C_S; from the two charge balance equations above, it is simple to derive *Equation 11* between the ideal and real sampled voltage on C_S:

Equation 11

$$\frac{V_{A2}}{V_A} = \frac{C_{P1} + C_{P2} + C_F}{C_{P1} + C_{P2} + C_F + C_S}$$

From this formula, in the worst case (when V_A is maximum, that is for instance 5 V), assuming to accept a maximum error of half a count, a constraint is evident on C_F value:

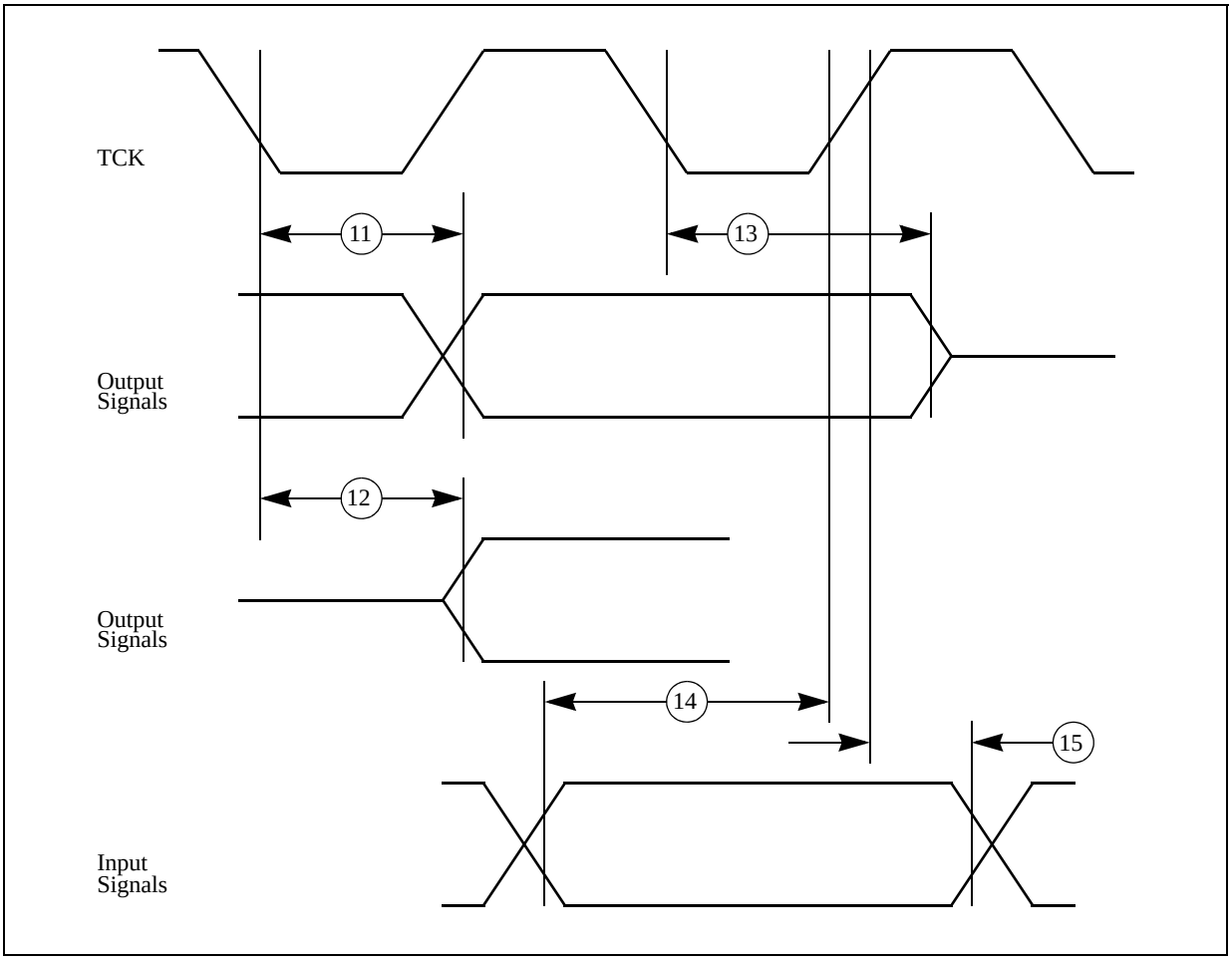
Equation 12

$$C_F > 8192 \bullet C_S$$

Table 27. ADC conversion characteristics

Symbol		Parameter	Conditions(1)	Min	Typ	Max	Unit
f_{CK}	SR	ADC Clock frequency (depends on ADC configuration) (The duty cycle depends on AD_CK(2) frequency)	—	3	—	60	MHz
f_s	SR	Sampling frequency	—	—	—	983.6(3)	KHz
t_{sample}	D	Sample time(4)	60 MHz	383	—	—	ns
t_{eval}	D	Evaluation time(5)	60 MHz	600	—	—	ns
C_S(6)	D	ADC input sampling capacitance	—	—	—	7.32	pF
C_{P1}(6)	D	ADC input pin capacitance 1	—	—	—	5(7)	pF
C_{P2}(6)	D	ADC input pin capacitance 2	—	—	—	0.8	pF
R_{SW1}(6)	D	Internal resistance of analog source	V_{REF} range = 4.5 to 5.5 V	—	—	0.3	kΩ
			V_{REF} range = 3.0 to 3.6 V	—	—	875	W
R_{AD}(6)	D	Internal resistance of analog source	—	—	—	825	W
INL	P	Integral non linearity	—	–3	—	3	LSB
DNL	P	Differential non linearity(8)	—	–1	—	2	LSB
OFS	T	Offset error	—	–6	—	6	LSB
GNE	T	Gain error	—	–6	—	6	LSB
IS1WINJ			(single ADC channel)				
	C	Max positive/negative injection		–3	—	3	mA

Figure 26. JTAG boundary scan timing



3.21.4 Nexus timing

Table 39. Nexus debug port timing(1)

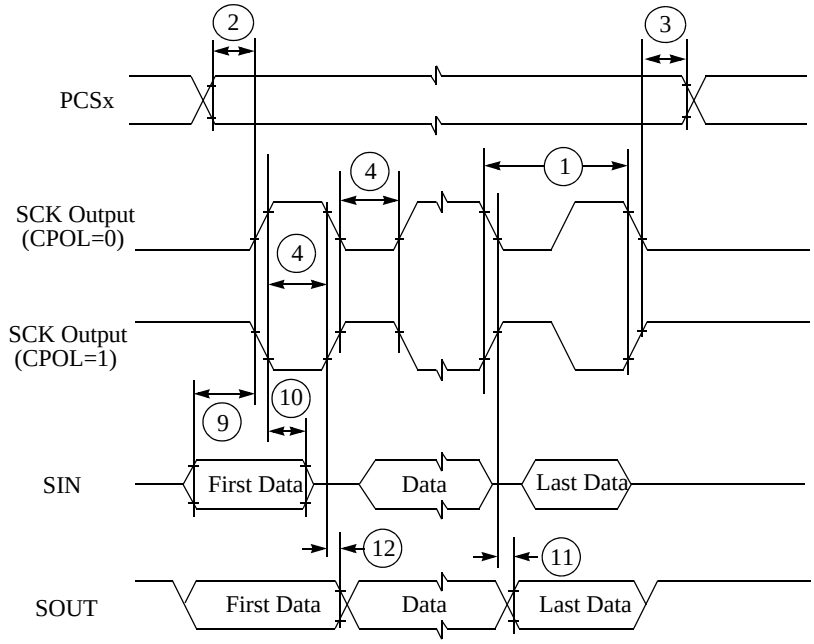
No.	Symbol		Parameter	Conditions	Min	Max	Unit
1	t_{MCYC}	D	MCKO Cycle Time	—	15.6	—	ns
2	t_{MDC}	D	MCKO Duty Cycle	—	40	60	%
3	t_{MDOV}	D	MCKO Low to MDO, $\overline{MSEO}$, $\overline{EVTO}$ Data Valid(2)	—	–0.1	0.25	t_{MCYC}
4	t_{EVTIPW}	D	$\overline{EVTI}$ Pulse Width	—	4.0	—	t_{TCYC}
5	t_{EVTOPW}	D	$\overline{EVTO}$ Pulse Width	—	1		t_{MCYC}
6	t_{TCYC}	D	TCK Cycle Time(3)	—	62.5	—	ns
7	t_{TDC}	D	TCK Duty Cycle	—	40	60	%
8	t_{NTDIS}, t_{NTMSS}	D	TDI, TMS Data Setup Time	—	8	—	ns

Table 41. DSPI timing (continued)

No.	Symbol		Parameter	Conditions	Min	Max	Unit
12	t_{HO}	D	Data hold time for outputs	Master (MTFE = 0)	–2	—	ns
				Slave	6	—	
				Master (MTFE = 1, CPHA = 0)	6	—	
				Master (MTFE = 1, CPHA = 1)	–2	—	

1. Slave Receive Only Mode can operate at a maximum frequency of 60 MHz. In this mode, the DSPI can receive data on SIN, but no valid data is transmitted on SOUT.

Figure 32. DSPI classic SPI timing — master, CPHA = 0



Note: The numbers shown are referenced in *Table 41*.

Table 45. Document revision history

Date	Revision	Changes
23-Mar-2011	6 (continued)	In the “Supply current characteristics (cut2)“ table: – Changed “$I_{DD\_LV\_MAX}$” to “$I_{DD\_LV\_MAX}$“; – Removed all “40-120 MHz” frequency ranges from the “Conditions” column; – Updated the “Max” values column; – Added parameter “$I_{DD\_LV\_TYP}$ + $I_{DD\_LV\_PLL}$“ with “P” classification and special footnote; – Changed all “25°C“ temperature conditions to “ambient”; – Added “T_J = 150 °C“ condition to parameters $I_{DD\_HV\_ADC}$, $I_{DD\_HV\_AREF}$, $I_{DD\_HV\_OSC}$, and $I_{DD\_HV\_FLASH}$. Changed the timing diagram in the “Main oscillator electrical characteristics” section to reference MTRANS assertion instead of V_{DDMIN}. Updated the jitter specs in the “FMPLL electrical characteristics“ table. In the “ADC conversion characteristics“ table, changed all parameters with units of “counts” to units of “LSB” and updated Min/Max values. Changed $I_{DD\_LV\_BIST}$ + $I_{DD\_LV\_PLL}$ operating current (for both cases) to TBD. In the “Supply current characteristics (cut2)” section, added a footnote that $I_{DD\_HV\_ADC}$ and $I_{DD\_HV\_AREF}$ represent the total current of both ADCs in the “Current consumption characteristics” table. In the “ADC conversion characteristics” table: – Changed DNL min from -2 to -1. – Changed OFS min from -2 to -6. – Changed OFS max from 2 to 6. – Changed GNE min from -2 to -6. – Changed GNE max from 2 to 6. – Changed SNR min from 69 to 67. – Changed TUE min (without current injection) from -6 to -8. – Changed TUE max (without current injection) from 6 to 8. – Changed TUE min (with current injection) from -8 to -10. Changed TUE max (with current injection) from 8 to 10.

Table 45. Document revision history

Date	Revision	Changes
01-Aug-2012	8 (cont.)	– In *Table 20: Voltage regulator electrical specifications*, changed the “Digital supply high voltage detector upper threshold low limit (After a destructive reset initialization phase completion)” from 1.43V to 1.38V. – Added *Table 20: Voltage regulator electrical specifications*. – Updated the IDD values in *Table 22: Current consumption characteristics*. Changed conditions text from “1.2 supplies during LBIST (full LBIST configuration)” to “1.2 V supplies” for all the IDD parameters except $I_{DD\_LV\_BIST}$+$I_{DD\_LV\_PLL}$. Added footnote in “Conditions” for the DPM mode. – Removed Cut references from the whole document. In *Table 27: ADC conversion characteristics*, changed the sampling frequency value from ‘1 MHz’ to ‘983.6 KHz’.
31-Jul-2013	9	– Updated *Table 20: Voltage regulator electrical specifications* (Voltage regulator electrical specifications) – Added Digital supply low voltage detector lower threshold and Digital supply low voltage detector upper threshold – Updated Main High Voltage Power-Low Voltage Detection value to 2.93 V – Replaced IEC with ISO26262 in *Section 1.1: Document overview*, – *Table 1* (SPC56XL60/54 device summary)-removed KGD – *Table 26* (16 MHz RC oscillator electrical characteristics) modified fRC values – Updated*Table 28* (Flash memory program and erase electrical specifications) – Updated *Table 27* (ADC conversion characteristics)-tconv to teval and associated footnote – Updated *Table 21* (DC electrical characteristics) – added VIH footnote – Updated IOL, IOH value for Fast pads – Updated *Table 33* (RESET sequences)-TDRB and TELRB – Updated *Table 20* (Voltage regulator electrical specifications)-combined ESR of external capacitor values – Updated *Section 3.16.1: Input Impedance and ADC Accuracy* -replaced fc by fs – *Table 7* (System pins)s-added footnote to RESET pin about weak pull down – Updated Injection current information in *Table 21* (DC electrical characteristics)-IINJ, *Table 9* (Absolute maximum ratings)-footnote 4 – Updated *Table 22* (Current consumption characteristics) for the following: – specified oscillator bypass mode and crystal oscillator mode – Updated STOP and HALT mode values – Added IDD_HV_PMU – footnote 2, footnote 3 – Added footnote $V_{DD\_HV\_ADRx}$ must always be applied and should be stable before LBIST starts. to *Table 10* (Recommended operating conditions (3.3 V)). – Added footnote to *Section 5: Ordering information* – Edit changes to *Section 3.6: Electromagnetic Interference (EMI) characteristics* – Updated *Equation 11*.

Table 45. Document revision history

Date	Revision	Changes
18-Sep-2013	10	– Updated Disclaimer.
07-Feb-2014	11	– Removed “TBC” symbol in *Table 9* and *Table 22* – Resolved some cross references.
08-Jul-2015	12	Editorial and formatting changes throughout document. *Chapter 1: Introduction*: – In *Table 1: SPC56ELx/SPC564Lx device summary* added the column for SPC56EL54 device *Chapter 3: Electrical characteristics*: – In *Table 9: Absolute maximum ratings*, added condition “Valid only for ADC pins” for V_{IN} Symbol. – Added *Section 3.4: Decoupling capacitors*. – *Figure 10: Input Equivalent Circuit*: changed “V_{DD}” to “V_{REF}” in Internal circuit scheme – In *Table 32: Pad AC specifications (3.3 V, IPP_HVE = 0)* updated footnote 1 and footnote 2. – Updated *Figure 13: Pad output delay* Updated Disclaimer.